•	Se	ar	ch	N	ot	es	5	

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/623,608	LIN ET AL.		
Examiner	Art Unit		
Donna V Lui	2675		

SEARCHED				
Class	Subclass	Date	Examiner	
345	166	10/5/2005	DL	
345	164	10/12/2005	DL	
345	160	10/12/2005	DL	

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
			-	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
345 East-Text Search (US-PGPUB; USPAT; USOCR; EPO; JPO; Derwent; IBM_TDB)	10/11/2005	DL	
345/160, 345/166 East-Text Search (US-PGPUB; USPAT; USOCR; EPO; JPO; Derwent; IBM_TDB)	10/11/2005	DL	
345/157, 345/163, 345/169 East-Text Search (US-PGPUB; USPAT; USOCR; EPO; JPO; Derwent; IBM_TDB)	10/5/2005	DL	
			
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